CY74FCT821T 10-BIT BUS-INTERFACE REGISTER WITH 3-STATE OUTPUTS

SCCS033B-MAY 1994 - REVISED NOVEMBER 2001

- Function, Pinout, and Drive Compatible With FCT, F Logic, and AM29821
- Reduced V_{OH} (Typically = 3.3 V) Version of Equivalent FCT Functions
- Edge-Rate Control Circuitry for Significantly Improved Noise Characteristics
- I_{off} Supports Partial-Power-Down Mode Operation
- Matched Rise and Fall Times
- Fully Compatible With TTL Input and Output Logic Levels
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- 64-mA Output Sink Current
 32-mA Output Source Current
- High-Speed Parallel Register With Positive-Edge-Triggered D-Type Flip-Flops
- 3-State Outputs

(TOP VIEW) 24 🛮 V_{CC} OE II 23 X Y₀ $D_0 \square 2$ $D_1 \square 3$ 22 X1 $D_2 \square 4$ 21 Y₂ 20 TY3 $D_3 \square 5$ D₄ **[**] 6 19 Y₄ D₅ [] 7 18 Y₅ $D_6 \square 8$ 17 Y₆ $D_7 \begin{bmatrix} 1 \\ 9 \end{bmatrix}$ 16 Y₇ D₈ 10 15 Y₈ D₉ [11 14 Y₉ GND [] 12 13 CP

P, Q, OR SO PACKAGE

description

This bus-interface register is designed to eliminate the extra packages required to buffer existing registers and provide extra data width for wider address/data paths or buses carrying parity. The CY74FCT821T is a 10-bit-wide buffered version of the popular CY74FCT374 function. This device is ideal for use as an output port requiring high I_{OL}/I_{OH}.

This device is designed for high-capacitance load drive capability, while providing low-capacitance bus loading at both inputs and outputs. Outputs are designed for low-capacitance bus loading in the high-impedance state.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

PIN DESCRIPTION

NAME	1/0	DESCRIPTION
D	_	D flip-flop data inputs
СР	0	Clock pulse for the register. Enters data into the register on the low-to-high clock transition.
Υ	0	Register 3-state outputs
ŌE	I	Output control. When \overline{OE} is high, the Y outputs are in the high-impedance state. When \overline{OE} is low, true register data is present at the Y outputs.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION

TA	PAC	KAGE [†]	SPEED (ns)	ORDERABLE PART NUMBER	TOP-SIDE Marking
	QSOP – Q	Tape and reel	6	CY74FCT821CTQCT	FCT821C
	SOIC - SO	Tube	6	CY74FCT821CTSOC	FCT821C
	3010 - 30	Tape and reel	6	CY74FCT821CTSOCT	FC1021C
	DIP – P	Tube	7.5	CY74FCT821BTPC	CY74FCT821BTPC
–40°C to 85°C	SOIC - SO	Tube	7.5	CY74FCT821BTSOC	FCT821B
	3010 - 30	Tape and reel	7.5	CY74FCT821BTSOCT	FC1021B
	QSOP – Q	Tape and reel	10	CY74FCT821ATQCT	FCT821A
	SOIC - SO	Tube	10	CY74FCT821ATSOC	FCT821A
	3010 - 30	Tape and reel	10	CY74FCT821ATSOCT	FUIOZIA

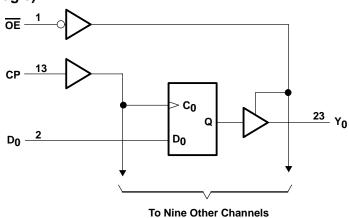
[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

	INPUTS			RNAL PUTS	FUNCTION
OE	D	СР	Q	Υ	
Н	Χ	1	L	Z	Z
Н	L	1	L	Z	
Н	Н	\uparrow	Н	Z	Lood
L	L	\uparrow	L	L	Load
L	Н	\uparrow	Н	Н	

H = High logic level, L = Low logic level, X = Don't care, \uparrow = Low-to-high transition, Z = High-impedance state

logic diagram (positive logic)





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absolute maximum rating over operating free-air temperature range (unless otherwise noted)

Supply voltage range to ground potential	0.5	V to 7 V
DC input voltage range		
DC output voltage range		
DC output current (maximum sink current/pin)		
Package thermal impedance, θ _{JA} (see Note 1): P package		
(see Note 2): Q package		
(see Note 2): SO package		46°C/W
Ambient temperature range with power applied, T _A	-65°C	to 135°C
Storage temperature range, T _{stg}	-65°C 1	to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
V _{IL}	Low-level input voltage			0.8	V
ІОН	High-level output current			-32	mA
lOL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51-3.

^{2.} The package thermal impedance is calculated in accordance with JESD 51-7.

CY74FCT821T 10-BIT BUS-INTERFACE REGISTER WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITION	s	MIN	TYP [†]	MAX	UNIT
VIK	V _{CC} = 4.75 V,	I _{IN} = -18 mA			-0.7	-1.2	V
V	V 475 V	I _{OH} = -32 mA		2			V
VOH	V _{CC} = 4.75 V	I _{OH} = -15 mA		2.4	3.3		V
VOL	V _{CC} = 4.75 V,	I _{OL} = 64 mA			0.3	0.55	V
V _{hys}	All inputs				0.2		V
lj	V _{CC} = 5.25 V,	V _{IN} = V _{CC}				5	μΑ
lіН	V _{CC} = 5.25 V,	V _{IN} = 2.7 V				±1	μΑ
Ι _Ι L	V _{CC} = 5.25 V,	$V_{IN} = 0.5 V$				±1	μΑ
lozh	V _{CC} = 5.25 V,	V _{OUT} = 2.7 V				10	μΑ
lozL	V _{CC} = 5.25 V,	V _{OUT} = 0.5 V				-10	μΑ
los [‡]	V _{CC} = 5.25 V,	V _{OUT} = 0 V		-60	-120	-225	mA
l _{off}	$V_{CC} = 0 V$,	V _{OUT} = 4.5 V				±1	μΑ
Icc	$V_{CC} = 5.25 \text{ V},$	$V_{IN} \le 0.2 V$,	$V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.1	0.2	mA
ΔlCC	V _{CC} = 5.25 V, V _{IN} =	3.4 V [§] , f ₁ = 0, Outputs op	oen		0.5	2	mA
I _{CCD} ¶	$\frac{V_{CC} = 5.25 \text{ V, One b}}{\text{OE} = \text{EN} = \text{GND, V}_{IN}}$	it switching at 50% duty c $1 \le 0.2 \text{ V or V}_{IN} \ge \text{V}_{CC} = 0$	cycle, Outputs open, 0.2 V		0.06	0.12	mA/ MHz
		One bit switching at f ₁ = 5 MHz	$V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		0.7	1.4	
\#	$V_{CC} = 5.25 \text{ V},$	at 50% duty cycle	$V_{IN} = 3.4 \text{ V or GND}$		1.2	3.4	A
IC#	Outputs open, OE = EN = GND	Eight bits switching at f ₁ = 2.5 MHz	$V_{IN} \le 0.2 \text{ V or} $ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$		1.6	3.2	mA
		at 50% duty cycle	V _{IN} = 3.4 V or GND		3.9	12.2	
C _i					5	10	pF
Co					9	12	pF

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

IC = Total supply current

I_{CC} = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input ($V_{IN} = 3.4 \text{ V}$)

 D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

Values for these conditions are examples of the I_{CC} formula.



Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

[§] Per TTL-driven input (V_{IN} = 3.4 V); all other inputs at V_{CC} or GND

This parameter is derived for use in total power-supply calculations.

[#] I_C = I_{CC} + Δ I_{CC} × D_H × N_T + I_{CCD} (f₀/2 + f₁ × N₁) Where:

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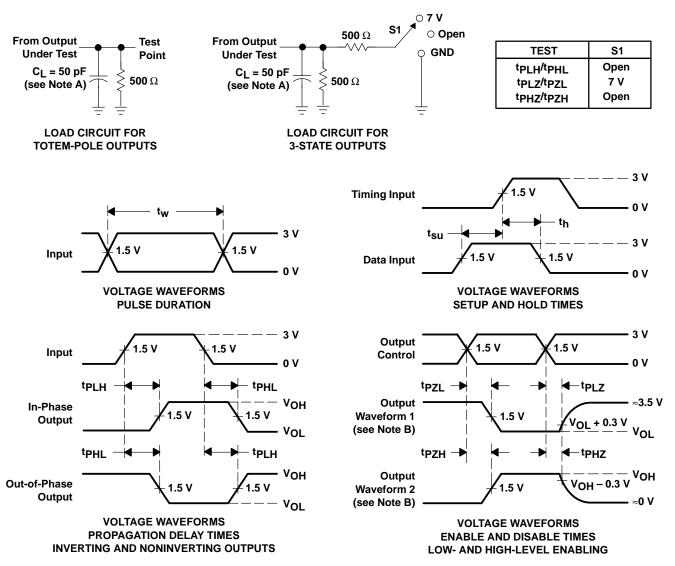
timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

	PARAMETER	TEST LOAD	CY74FCT821AT		CY74FCT821BT		CY74FCT821CT		UNIT	
	PARAMETER		TEST LOAD	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
t _W	Pulse duration	СР	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	7		6		6		ns
t _{su}	Setup time, before CP↑	Data	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	4		3		3		ns
th	Hold time, after CP↑	Data	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega$	2		1.5		1.5		ns

switching characteristics over operating free-air temperature range (see Figure 1)

DADAMETER	FROM	то	TEST LOAD	CY74FC1	821AT	CY74FCT	821BT	CY74FC1	821CT	UNIT
PARAMETER	(INPUT)	(OUTPUT)	TEST LOAD	MIN	MAX	MIN	MAX	MIN	MAX	UNII
tPLH	СР	Y	C _L = 50 pF,		10		7.5		6	ns
t _{PHL}	5	ī	$R_L = 500 \Omega$		10		7.5		6	115
tPLH	СР	Y	C _L = 300 pF,		20		15		12.5	ns
t _{PHL}	Gr .	'	$R_L = 500 \Omega$		20		15		12.5	115
^t PZH	ŌE	Υ	$C_{L} = 50 \text{ pF},$		12		8		7	ns
tPZL	OL	,	$R_L = 500 \Omega$		12		8		7	115
^t PZH	OE	Y	$C_L = 300 \text{ pF},$		23		15		12.5	ns
tpzL	OL	'	$R_L = 500 \Omega$		23		15		12.5	110
t _{PHZ}	ŌE	Υ	C _L = 5 pF,		7		6.5		6	ns
tPLZ) 	'	$R_L = 500 \Omega$		7		6.5		6	115
^t PHZ	ŌĒ	Υ	$C_L = 50 \text{ pF},$		8		7.5		6.5	ns
tPLZ) U	<u>'</u>	$R_L = 500 \Omega$		8		7.5		6.5	115

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CY74FCT821ATSOC	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT821A	Samples
CY74FCT821BTSOC	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT821B	Samples
CY74FCT821CTQCT	ACTIVE	SSOP	DBQ	24	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	FCT821C	Samples
CY74FCT821CTSOC	ACTIVE	SOIC	DW	24	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT821C	Samples
CY74FCT821CTSOCT	ACTIVE	SOIC	DW	24	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	FCT821C	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CY74FCT821CTQCT	SSOP	DBQ	24	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CY74FCT821CTSOCT	SOIC	DW	24	2000	330.0	24.4	10.75	15.7	2.7	12.0	24.0	Q1

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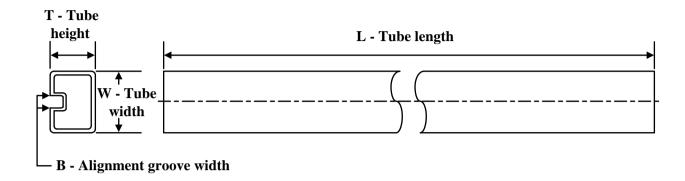
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CY74FCT821CTQCT	SSOP	DBQ	24	2500	356.0	356.0	35.0
CY74FCT821CTSOCT	SOIC	DW	24	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CY74FCT821ATSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6
CY74FCT821BTSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6
CY74FCT821CTSOC	DW	SOIC	24	25	506.98	12.7	4826	6.6

DW (R-PDSO-G24)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.



DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



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